

Test report No.

: 27KE0162-HO-A

Page

: 1 of 60

Issued date FCC ID : August 8, 2007

: EJE-BPAD05

# **RADIO TEST REPORT**

Test Report No.: 27KE0162-HO-A

Applicant

Fujitsu Limited

Type of Equipment

**B-PAD** 

Model No.

CA06178-A521

FCC ID

EVE DD I DO

Test standard

EJE-BPAD05

:

:

FCC Part 15 Subpart C 2007

Section 15.207, Section 15.247

**Test Result** 

: Complied

- This test report shall not be reproduced in full or partial, without the written approval of UL Japan, Inc.
- 2. The results in this report apply only to the sample tested.
- 3. This sample tested is in compliance with the above regulation.
- 4. The test results in this report are traceable to the national or international standards.

Date of test:

June 21 to 29, 2007

Tested by:

Approved by:

Shinya Watanabe

EMC Services

Tetsuo Maeno

Site Manager of EMC Services

This laboratory is accredited by the NVLAP LAB CODE 200572-0, U.S.A. The tests reported herein have been

performed in accordance with its terms of accreditation.

\*As for the range of Accreditation in NVLAP, you may refer to the WEB address, http://uljapan.co.jp/emc/nvlap.htm

Hisayoshi Sato EMC Services

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

NVLAP LAB CODE: 200572-0

Telephone

: +81 596 24 8116

Facsimile

: +81 596 24 8124

MF060b (18.06.07)

Test report No. : 27KE0162-HO-A : 2 of 60 Page : August 8, 2007 : EJE-BPAD05 Issued date

FCC ID

CONTENTS	PAGE
SECTION 1: Client information	3
SECTION 2: Equipment under test (E.U.T.)	
SECTION 3: Test specification, procedures & results	
SECTION 4: Operation of E.U.T. during testing	
SECTION 5: Conducted Emission	
SECTION 6: Spurious Emission	
SECTION 7: Bandwidth	
SECTION 8: Maximum Peak Output Power	
SECTION 9: Peak Power Density	
APPENDIX 1: Photographs of test setup	
Conducted Emission	
Spurious Emission (Radiated)	
Worst Case Position (Horizontal: X-axis/ Vertical: Y-axis)	
APPENDIX 2: Data of EMI test	
Conducted Emission	
6dB Bandwidth	
Maximum Peak Output Power	
Radiated Spurious Emission (below 1GHz)	
Radiated Spurious Emission (above 1GHz)	
Conducted Spurious Emission	
Conducted emission Band Edge compliance	
Power Density	
· · · · · · · · · · · · · · · · · · ·	
99%Occupied Bandwidth	

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone Facsimile : +81 596 24 8116 : +81 596 24 8124

Test report No. : 27KE0162-HO-A
Page : 3 of 60
Issued date : August 8, 2007
FCC ID : EJE-BPAD05

## **SECTION 1: Client information**

Company Name : Fujitsu Limited

Address : 4-1-1 Kamikodanaka, Nakahara-ku Kawasaki-shi, Kanagawa 211-8588 Japan

Telephone Number : +81-44-754-3885 Contact Person : Ken Uchihara

# **SECTION 2:** Equipment under test (E.U.T.)

#### 2.1 Identification of E.U.T.

Type of Equipment : B-PAD Model No. : CA06178-A521

Serial No. : 0001

Rating : AC100 – 240V, DC3.7V (Battery)

Country of Manufacture : Japan
Receipt Date of Sample : July 18, 2007
Condition of EUT : Production model

Modification of EUT : No modification by the test lab.

#### 2.2 Product Description

Model No: CA06178- A521 (referred to as the EUT in this report) is the B-PAD.

The EUT contains IEEE802.11b/g Wireless LAN and Bluetooth modules. Those modules do not transmit simultaneously.

The EUT has a variant model, CA06178-A621. The difference in two models is model name only.

The EUT is a PDA for business. This unit is carrying the newest Intel XScale in CPU and adopting WindowsCE.5.0 as operating system. Moreover, the packaging of various I/O and I/F to the EUT is carried out to PDA size.

- 3.5 inch TFT color transmissive LCD (320x240 pixel), LED back light, touch panel
- Built in numeric keypad
- Integrated Magnetic Card Reader
- Barcode Reader
- Bluetooth Module
- IEEE802.11b/g Wireless LAN Module

## Clock frequencies of the EUT are as shown on the following table:

CPU	520MHz, 13MHz, 125MHz, 32.768kHz
3.5 inch TFT color transmissive LCD (320x240 pixel),	6.25MHz
LED back light, touch panel	
Built in numeric keypad	4.033355MHz
Audio Codec	24.576MHz
CF Card	48MHz
Integrated Magnetic Card Reader	4.915MHz
IEEE802.11b/g Wireless LAN Module	40MHz
Bluetooth Module	16MHz, 32.768kHz

# UL Japan, Inc.

# **Head Office EMC Lab.**

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No. : 27KE0162-HO-A
Page : 4 of 60
Issued date : August 8, 2007
FCC ID : EJE-BPAD05

		IEEE802.11b/g Wireless LAN	
Frequency band Lower limit		2412MHz	
	Upper limit	2462MHz	
Type of Modulation		DSSS, OFDM	
Antenna Type		λ/4 dielectric chip antenna	
Antenna Connector Type		W. FL	
Antenna Gain		1.8dBi	
ITU code		G1D(DSSS), D1D(OFDM)	
Power Supply (Inner)		DC 3.3V	

		Bluetooth	
Frequency band	Lower limit	2402MHz	
	Upper limit	2480MHz	
Bandwidth & Channel spacing		1MHz & 1MHz / CH	
Type of Modulation		FHSS	
Antenna Type		λ/4 dielectric chip antenna	
Antenna Connector Type		U. FL	
Antenna Gain		-4.3dBi	
ITU code		F1D	
Power Supply (Inner)		DC 3.3V	

<sup>\*</sup> For Bluetooth module test, please see UL Japan Test Report No. 27KE0162-HO-C.

# UL Japan, Inc. Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No. : 27KE0162-HO-A
Page : 5 of 60
Issued date : August 8, 2007
FCC ID : EJE-BPAD05

# **SECTION 3: Test specification, procedures & results**

#### 3.1 Test Specification

Test Specification : FCC Part15 Subpart C: 2007

Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional

Radiators

Section 15.207 Conducted limits

Section 15.247 Operation within the bands 902-928MHz,

2400-2483.5MHz, and 5725-5850MHz

#### FCC 15.31 (e)

This EUT provides stable voltage(DC3.3V) constantly to RF Modules regardless of input voltage. Therefore, this EUT complies with the requirement.

# FCC Part 15.203 Antenna requirement

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

# UL Japan, Inc. Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No. : 27KE0162-HO-A Page : 6 of 60 **Issued date** : August 8, 2007 : EJE-BPAD05 FCC ID

#### 3.2 **Procedures and results**

No.	Item	Test Procedure	Specification	Remarks	Deviation	Worst margin	Results
1	Conducted emission	FCC: ANSI C63.4:2003 7. AC powerline conducted emission measurements	FCC: Section 15.207	-	N/A	8.3dB 0.50265MHz	Complied
		IC: RSS-Gen 7.2.2	IC: RSS-Gen 7.2.2			AV, N	
2	6dB Bandwidth	FCC: ANSI C63.4:2003 13. Measurement of intentional radiators	FCC: Section 15.247(a)(2)	Conducted	N/A		Complied
		IC: RSS-Gen 4.6.2	IC: RSS-210 A8.2(a)				
3	Maximum Peak Output Power	FCC: ANSI C63.4:2003 13. Measurement of intentional radiators	FCC: Section 15.247(b)(3)	Conducted	N/A	-	Complied
		IC: RSS-Gen 4.8	IC: RSS-210 A8.4(4)				
4	Restricted Band Edges	FCC: ANSI C63.4:2003 13. Measurement of intentional radiators	FCC: Section 15.247 (d)	Conducted/ Radiated	N/A	See data.	Complied
		IC: -	IC: RSS-210 A8.5				
5	Power Density	FCC: ANSI C63.4:2003 13. Measurement of intentional radiators	FCC: Section 15.247 (e)	Conducted	N/A		Complied
		IC: -	IC: RSS-210 A8.2(b)				
6	Spurious Emission	FCC: ANSI C63.4:2003 13. Measurement of intentional radiators	FCC: Section15.247(d)	Conducted/ Radiated	N/A	[Tx] 3.2 dB 2483.5MHz	Complied
		IC: RSS-Gen 4.9 RSS-Gen 4.10	IC: RSS-210 A8.5 RSS-Gen 7.2.1 and 7.2.3			Hori., AV [Rx] 3.5dB 311.990MHz Hori., QP	

<sup>\*</sup>These tests were also referred to "Guidance on Measurement of Digital Transmission Systems Operating under Section15.247".

\*These tests were performed without any deviations from test procedure except for additions or exclusions.

#### 3.3 Addition to standards

N	. Item	<b>Test Procedure</b>	Specification	Remarks	Deviation	Worst margin	Results
1	99% Occupied	<ic>RSS-Gen 4.6.1</ic>	<ic>RSS-Gen 4.6.1</ic>	Conducted	N/A	N/A	Complied
	Band Width						

# UL Japan, Inc. **Head Office EMC Lab.**

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No. : 27KE0162-HO-A
Page : 7 of 60
Issued date : August 8, 2007
FCC ID : EJE-BPAD05

#### 3.4 Uncertainty

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

#### Conducted Emission

The measurement uncertainty for this test is  $\pm 2.66$ dB.

The data listed in this test report has enough margin, more than the site margin.

#### Spurious Emission (Radiated)

The measurement uncertainty for this test using Biconical antenna is  $\pm 4.59$ dB(3m).

The measurement uncertainty for this test using Logperiodic antenna is  $\pm 4.62 dB(3m)$ .

The measurement uncertainty for this test using Horn antenna is  $\pm 5.27 dB$ .

The data listed in this report meets the limits unless the uncertainty is taken into consideration.

#### Other test except Conducted Emission and Spurious Emission (Radiated)

The measurement uncertainty for this test is  $\pm 3.0$ dB.

#### 3.5 Test Location

UL Japan, Inc. Head Office EMC Lab. \*NVLAP Lab. code: 200572-0

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

 Telephone
 : +81 596 24 8116
 Facsimile
 : +81 596 24 8124

 FCC
 IC Registration
 Width x Depth x
 Size

	FCC Registration Number	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	313583	IC4247	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	IC4247-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	IC4247-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	IC4247-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-

<sup>\*</sup> Size of vertical conducting plane (for Conducted Emission test): 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

# 3.6 Test set up, Test instruments and Data of EMI

Refer to APPENDIX 1 to 3.

# UL Japan, Inc. Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No. : 27KE0162-HO-A
Page : 8 of 60
Issued date : August 8, 2007
FCC ID : EJE-BPAD05

# **SECTION 4: Operation of E.U.T. during testing**

#### 4.1 Operating Modes

The mode used for test: Transmitting mode 11b (CCK 11Mbps (Worst), Packet type: Maximum, Payload: PN9)

- Low Channel : 2412MHz(Ch1) - Mid Channel : 2437MHz(Ch6) - High Channel : 2462MHz(Ch11)

Transmitting mode 11g (OFDM 54Mbps (Worst), Packet type: Maximum, Payload: PN9)

- Low Channel : 2412MHz(Ch1) - Mid Channel : 2437MHz(Ch6) - High Channel : 2462MHz(Ch11)

Receiving mode 11b/g
- Mid Channel : 2437MHz

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

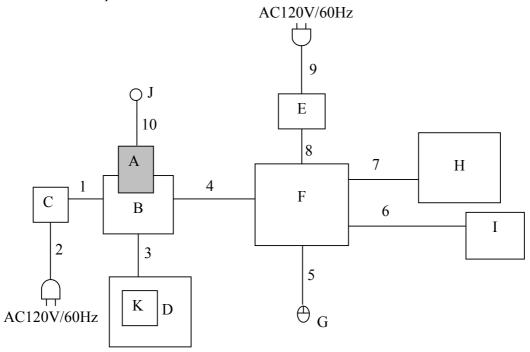
<sup>\*</sup>As a result of preliminary test, the formal test was performed with the above transmitting modes, which had the maximum rated power.

Test report No. : 27KE0162-HO-A Page : 9 of 60

Page : 9 of 60 Issued date : August 8, 2007 FCC ID : EJE-BPAD05

# 4.2 Configuration and peripherals

# [Conducted Emission test]



# [Radiated Emission test]

# [Antenna Terminal Conducted test]



<sup>\*</sup> Cabling and setup were taken into consideration and test data was taken under worse case conditions.

**Head Office EMC Lab.** 

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No. : 27KE0162-HO-A
Page : 10 of 60
Issued date : August 8, 2007
FCC ID : EJE-BPAD05

**Description of EUT and Support equipment** 

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	B-PAD	CA06178-A521	0001	Fujitsu Frontech Limited	EUT
В	CRADLE	KD02902-299	1	Fujitsu Frontech Limited	-
C	AC Adapter	CP235934-01	05202854A	Fujitsu Frontech Limited	-
D	Battery Charger	CA05951-7081	1	TOCAD ENERGY CO., LTD	
Е	AC Adapter	02K6750	11S02K6750Z1Z	IBM	-
E			2UP2950KD		
F	PC	T23 (= 2647-LJ3)	97-ALT9W	IBM	-
G	Mouse	M-SA551	LZB92663446	LOGITECH	-
Н	Printer	BJF860	K10201	Canon	-
T	Monitor	17inch	0D5431-64180-	Dell	-
1			59T-197C		
J	Head set	-	-	-	-
K	Battery	CA50601-1003	-	TOCAD ENERGY CO., LTD	-

List of cables used

	i cables useu			
No.	Name	Length (m)	Shi	ield
			Cable	Connector
1	DC cable	1.0	Unshielded	Unshielded
2	AC cable	2.0	Unshielded	Unshielded
3	DC cable	0.18	Unshielded	Unshielded
4	USB cable	1.0	Shielded	Shielded
5	Mouse cable	2.0	Unshielded	Unshielded
6	Monitor cable	1.5	Unshielded	Unshielded
7	Parallel cable	1.0	Unshielded	Unshielded
8	DC cable	2.0	Unshielded	Unshielded
9	AC cable	1.0	Unshielded	Unshielded
10	Earphone cable	1.2	Unshielded	Unshielded

# UL Japan, Inc. Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No. : 27KE0162-HO-A
Page : 11 of 60
Issued date : August 8, 2007
FCC ID : EJE-BPAD05

#### **SECTION 5: Conducted Emission**

#### **Test Procedure and conditions**

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 80cm above the conducting ground plane.

The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT, including peripherals aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from a Line Impedance Stabilization Network (LISN)/ Artificial mains Network (AMN) and excess AC cable was bundled in center.

#### For the tests on EUT with other peripherals (as a whole system)

I/O cable and AC cables that were connected to the peripherals were bundled in center. They were folded back and forth forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane. All unused 50ohm connectors of the LISN(AMN) were resistivity terminated in 50ohm when not connected to the measuring equipment.

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT in a Semi Anechoic Chamber or a Measurement Room.

The EUT was connected to a LISN (AMN).

An overview sweep with peak detection has been performed.

Detector : quasi-peak and average detector (IF BW 9 kHz)

Measurement range : 0.15-30MHz Test data : APPENDIX 2

Test result : Pass

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No. : 27KE0162-HO-A
Page : 12 of 60
Issued date : August 8, 2007
FCC ID : EJE-BPAD05

### **SECTION 6: Spurious Emission**

#### [Conducted]

#### **Test Procedure**

The Out of Band Emission was measured with a spectrum analyzer connected to the antenna port.

Test data : APPENDIX 2

Test result : Pass

#### [Radiated]

#### **Test Procedure**

EUT was placed on a urethane platform of nominal size, 0.5m by 1.0m, raised 80cm above the conducting ground plane. The Radiated Electric Field Strength intensity has been measured in a Semi Anechoic Chamber with a ground plane and at a distance of 3m(Below 10GHz) and 1m(Upper 10GHz).

The height of the measuring varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer (in linear mode).

The test was made with the detector (RBW/VBW) in the following table.

When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

In any 100kHz bandwidth outside the frequency band in which the spread spectrum intentional radiator is operating, the radio frequency power that is produced by the intentional radiator confirmed 20dB below that in the 100kHz bandwidth within the band that contains the highest level of the desired power, based on a radiated measurement.

20dBc was applied to the frequency over the limit of FCC 15.209 / Table 2 of RSS-210 2.7 (IC) and outside the restricted band of FCC 15.205 / Table 1 of RSS-210 2.7 (IC).

Frequency	Below 1GHz	Above 1GHz
Instrument used	Test Receiver / Spectrum Analyzer	Spectrum Analyzer
Detector	QP: BW 120kHz(T/R)	PK: RBW:1MHz/VBW: 1MHz
IF Bandwidth	20dBc : RBW: 100kHz	AV: RBW:1MHz/VBW:10Hz
	VBW: 300kHz (S/A)	20dBc: RBW:100kHz/VBW:300kHz

The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

Test data : APPENDIX 2

Test result : Pass

# UL Japan, Inc. Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Test report No. : 27KE0162-HO-A
Page : 13 of 60
Issued date : August 8, 2007
FCC ID : EJE-BPAD05

# **SECTION 7: Bandwidth**

#### **Test Procedure**

The bandwidth was measured with a spectrum analyzer connected to the antenna port.

Test data : APPENDIX 2

Test result : Pass

# **SECTION 8: Maximum Peak Output Power**

#### **Test Procedure**

The Maximum Peak Output Power was measured with a power meter (tested bandwidth: 50MHz) connected to the antenna port.

It was measured based on "Power Output Option 1" of "Guidance on Measurement of Digital Transmission Systems Operating under Section15.247".

Test data : APPENDIX 2

Test result : Pass

# **SECTION 9: Peak Power Density**

# [Conducted]

#### **Test Procedure**

The Peak Power Density was measured with a spectrum analyzer connected to the antenna port.

It was measured based on "PSD Option 1" of "Guidance on Measurement of Digital Transmission Systems Operating under Section15.247".

Test data : APPENDIX 2

Test result : Pass

# UL Japan, Inc.

**Head Office EMC Lab.** 

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN